

Technical Specifications



Element range	Mo excitation: Al to U (with exception of Nb to Ru)
Concentration	ppb to 100 %
Detection limit	< 2 pg Nickel
Sample types	Liquids, suspensions, powders, particles, metals, thin layers, tissues, wipes, filters etc.
Sample volume	Liquids and suspensions from 1 µl to 50 µl Particles up to 100 µm in diameter, powders up to 10 µg
Sample carrier	25 quartz and 100 acrylic glass carriers (30 mm diameter) included in delivery
Sample changer	Manual version for single samples Automatic version with cassette for up to 25 samples
X-ray tube	50 W metal-ceramic, max. 50 kV, 1 mA air-cooled, Mo target
X-ray optics	Multilayer monochromator
Detector	Peltier-cooled XFlash® Silicon Drift Detector No need for liquid nitrogen 60 mm² detector area Energy resolution < 149 eV at 100 kcps (Mn Kα)
Interface	Data exchange by RS232 serial interface Sample changer with RS232 (automatic version)
Mains	100/240 V, 50/60 Hz, max. power consumption 180 W
Size	300 mm x 590 mm x 450 mm (height x width x depth)
Weight	39 kg
Accessories	Washing cassette for sample carriers Sample cassette for 25 carriers Starter set for TXRF (pipettes, tips, tubes, mortar, spatula)

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